Display Elektronik GmbH

DATA SHEET

OLED MODULE

DEP 128032A-B

2,2" - OLED

Product Specification

Ver.: 3

Revision History

VERSION	DATE	REVISED PAGE NO.	Note
0	12.10.2013		First Release
1	30.05.2014		Update Rev.
2	16.06.2014		Add Low Temperature storage.
3	07.12.2015		Modify Lifetime

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1. General Specification

The Features is described as follow:

■ Module Dimension: 62.00 x 24.00 x 2.35 mm

Viewing Area: 57.02 x 15.10 mmActive Area: 55.018 x 13.098 mm

Dot Matrix: 128 x 32 Dots
 Dot Size: 0.408 x 0.388 mm
 Dot Pitch: 0.43 x 0.41 mm

■ Duty: 1/32

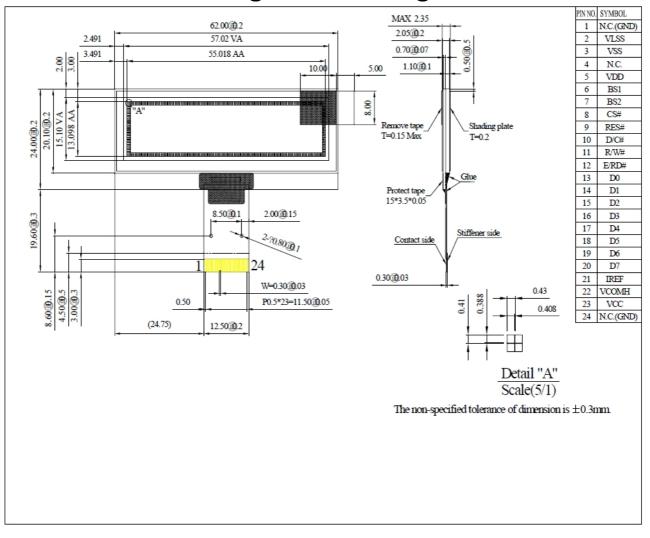
■ Display Color: OLED (Blue)

2. Interface Pin Function

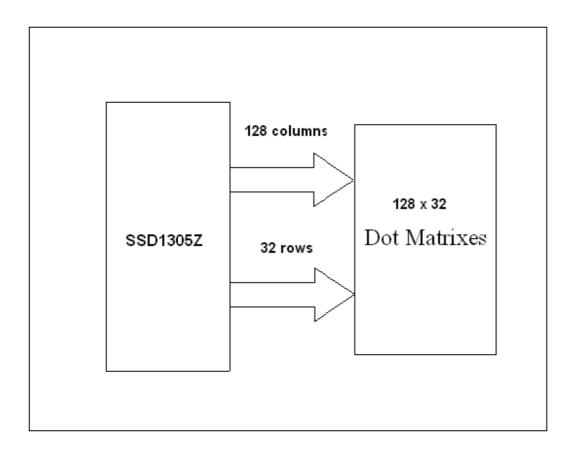
No.	Symbol		Function				
1	N.C.(GND)	No conne	No connection				
2	VLSS		his is an analog ground pin. It should be connected to VSS externally.				
3	VSS	Ground.					
4	N.C.	No conne	ection				
5	VDD	Power su	pply pin for core	logic operation			
6	BS1		icating Protocol S ns are MCU inter	face selection ir			wing
			68XX-parallel	80XX-parallel	Serial	I2C	
7	BS2	BS1	0	1	0	1	
		BS2	1	1	0	0	
8	CS#		s the chip select				
9	RES#	of the chi Keep this operation		onnect to VDDI	D) during	normal	
10	D/C#	connect to is pulled command	This is Data/Command control pin. When it is pulled HIGH (i.e. connect to VDDIO), the data at D[7:0] is treated as data. When it is pulled LOW, the data at D[7:0] will be transferred to the command register.				
11	R/W#	This is re interface. When into used as for carried or and write selected, operation selected. When se VSS.	When serial interface is selected, this pin must be connected to				
12	E/RD#	used as t when this	erfacing to a 680 he Enable (E) sig s pin is pulled HIC hip is selected.	gnal. Read/write	operatio	n is initia	

		When connecting to an 8080-microprocessor, this pin receives the Read (RD#) signal. Read operation is initiated when this pin is pulled LOW and the chip is selected. When serial interface is selected, this pin must be connected to VSS.
13	D0	The second O bit bit discretional data have to be a consected to the
14	D1	These are 8-bit bi-directional data bus to be connected to the
15	D2	microprocessor's data bus.
16	D3	When serial interface mode is selected, D0 will be the serial clock input: SCLK; D1 will be the serial data input: SDIN and D2
17	D4	should be left opened. When I2C mode is selected, D2, D1
18	D5	should be field together and serve as SDAout, SDAin in
19	D6	application and D0 is the serial clock input, SCL.
20	D7	application and 20 to the contain block input, coe.
21	IREF	This is segment output current reference pin. A resistor should be connected between this pin and VSS to maintain the IREF current at 10uA.
22	VCOMH	The pin for COM signal deselected voltage level. A capacitor should be connected between this pin and VSS.
23	VCC	Power supply for panel driving voltage. This is also the most positive power voltage supply pin.
24	N.C.(GND)	No connection

3. Counter Drawing & Block Diagram



FUNCTION BLOCK DIAGRAM



^{*}For more information, please refer to Application Note on request.

4. Absolute Maximum Ratings

Parameter	Symbol	Min	Max	Unit	Notes
Supply Voltage for Logic	V_{DD}	-0.3	4	V	1, 2
Supply Voltage for Display	V _{CC}	0	15	V	1, 2
Operating Temperature	T_OP	-40	+80	°C	-
Storage Temperature	T _{STG}	-40	+80	°C	-

Note 1: All the above voltages are on the basis of "VSS = 0V".

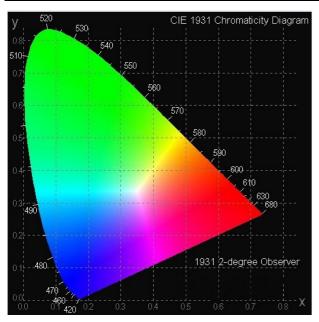
Note 2: When this module is used beyond the above absolute maximum ratings, permanent breakage of the module may occur. Also, for normal operations, it is desirable to use this module under the conditions according to Section6 "Electrical Characteristics". If this module is used beyond these conditions, malfunctioning of the module can occur and the reliability of the module may deteriorate

5. Electrical Characteristics

Item	Symbol	Condition	Min	Тур	Max	Unit
Supply Voltage for Logic	VDD	_	2.8	3.0	3.3	V
Supply Voltage for Display	VCC	_	9	10	11	V
High Level Input	VIH	_	0.8×VDD	_	VDD	V
Low Level Input	VIL	_	0	_	0.2×VDD	V
High Level Output	VOH	_	0.9×VDD	_	VDD	V
Low Level Output	VOL	_	0	_	0.1×VDD	٧
50% Check Board operatir Current	VCC =10V	18	20	25	mA	

6. Optical Characteristics

Item	Symbol	Condition	Min	Тур	Max	Unit	
View Angle	(V)θ	_	160	_	_	deg	
View / trigic	(Η)φ	_	160	_	_	deg	
Contrast Ratio	CR	Dark	2000:1	_	_	_	
Response Time	T rise	_	_	10	_	μs	
Tresponde Time	T fall	_	_	10 — μs 10 — μs 100 — cd/m2 0.16 0.20 —			
Display with 50% check E	Board Brightness		80				
CIEx(Blue)	(CIE1931)	0.12	0.16	0.20	_		
CIEy(Blue)		(CIE1931)	0.19	0.23	0.27	_	



7. OLED Lifetime

ITEM	Conditions	Min	Тур	Remark
Operating Life Time	Ta=25°C / Initial 50% check Board Typical Brightness Value	20,000 Hrs	-	Note

Note:

- 1. Life time is defined the amount of time when the luminance has decayed to <50% of the initial value.
- 2. This analysis method uses life data obtained under accelerated conditions to extrapolate an estimated probability density function (*pdf*) for the product under normal use conditions.
- 3. Screen saving mode will extend OLED lifetime.

8. Reliability

Content of Reliability Test

l Test		
Content of Test	Test Condition	Applicable Standard
Endurance test applying the high storage temperature for a long time.	80°C 240hrs	
Endurance test applying the low storage temperature for a long time.	-40°C 240hrs	
Endurance test applying the electric stress (Voltage & Current) and the thermal stress to the element for a long time.	80°C 240hrs	
Endurance test applying the electric stress under low temperature for a long time.	-40°C 240hrs	
Endurance test applying the high temperature and high humidity storage for a long time.	60°C,90%RH 240hrs	
Endurance test applying the low and high temperature cycle. -40°C 25°C 80°C 30min 5min 30min 1 cycle	-40°C/80°C 100 cycles	
st		
Endurance test applying the vibration during transportation and using.	10~22Hz→1.5mmp-p 22~500Hz→1.5G Total 0.5hr	
Constructional and mechanical endurance test applying the shock during transportation.	50G Half sin wave 11 ms 3 times of each direction	
Endurance test applying the atmospheric pressure during transportation by air.	115mbar 40hrs	
Endurance test applying the electric stress to the terminal.	VS=800V,RS=1.5kΩ CS=100pF 1 time	
	Endurance test applying the high storage temperature for a long time. Endurance test applying the low storage temperature for a long time. Endurance test applying the electric stress (Voltage & Current) and the thermal stress to the element for a long time. Endurance test applying the electric stress under low temperature for a long time. Endurance test applying the high temperature and high humidity storage for a long time. Endurance test applying the low and high temperature cycle. -40°C 25°C 80°C 30min 5min 30min 1 cycle st Endurance test applying the vibration during transportation and using. Constructional and mechanical endurance test applying the shock during transportation. Endurance test applying the atmospheric pressure during transportation by air.	Endurance test applying the high storage temperature for a long time. Endurance test applying the low storage temperature for a long time. Endurance test applying the electric stress (Voltage & Current) and the thermal stress to the element for a long time. Endurance test applying the electric stress under low temperature for a long time. Endurance test applying the high temperature and high humidity storage for a long time. Endurance test applying the low and high temperature cycle. -40°C 25°C 80°C -40°C/80°C 100 cycles st Endurance test applying the vibration during transportation and using. Constructional and mechanical endurance test applying the shock during transportation. Endurance test applying the atmospheric pressure during transportation by air. VS=800V,RS=1.5kΩ CS=100pF

^{***} Supply voltage for OLED system =Operating voltage at 25°C

Test and measurement conditions

- 1. All measurements shall not be started until the specimens attain to temperature stability. After the completion of the described reliability test, the samples were left at room temperature for 2 hrs prior to conducting the failure test at 23±5°C; 55±15% RH.
- 2. All-pixels-on is used as operation test pattern.
- 3. The degradation of Polarizer are ignored for High Temperature storage, High Temperature/ Humidity Storage, Temperature Cycle

Evaluation criteria

- 1. The function test is OK.
- 2. No observable defects.
- 3. Luminance: > 50% of initial value.
- 4. Current consumption: within ± 50% of initial value.

APPENDIX:

RESIDUE IMAGE

Because the pixels are lighted in different time, the luminance of active pixels may reduce or differ from inactive pixels. Therefore, the residue image will occur. To avoid the residue image, every pixel needs to be lighted up uniformly.

9. Inspection Specification

NO	Item	Criterion						AQL
01	Electrical Testing	 1.1 Missing vertical, horizontal segment, segment contrast defect. 1.2 Missing character, dot or icon. 1.3 Display malfunction. 1.4 No function or no display. 1.5 Current consumption exceeds product specifications. 1.6 OLED viewing angle defect. 1.7 Mixed product types. 1.8 Contrast defect. 					0.65	
02	Black or white spots on OLED (display only)	 2.1 White and black spots on display ≤0.25mm, no more than three white or black spots present. 2.2 Densely spaced: No more than two spots or lines within 3mm. 					2.5	
03	OLED black spots, white spots, contamina tion (non-display)	3.1 Round type : following drawing Φ=(x+y)/2		0 ¢	IZE 0≤0.10 .10< 0≤0.20 .20< 0≤0.25 .25<Φ	Accep TY Accep dense 2		
		3.2 Line type : (A	s following Length $$ L \leq 3.0 L \leq 2.5 $$	Width W≦0 0.02 <	0.02 <w≦0.03 <w≦0.05< td=""><td>Acceptal Accept r 2 As round</td><td></td><td>2.5</td></w≦0.05<></w≦0.03 	Acceptal Accept r 2 As round		2.5
04	Polarizer bubbles	If bubbles are vis judge using black specifications, no to find, must chec specify direction.	spot t easy	0.50 1.00	0.20 <Φ≦0.50 <Φ≦1.00	_ ·	ble Q TY no dense	2.5

NO	Item	Criterion			AQL
05	Scratches	Follow NO.3 OLED b	lack spots, white spot	s, contamination	
		k: Seal width t L: Electrode pad leng			
		6.1 General glass chi 6.1.1 Chip on panel s	•	ween panels:	
		7: Chin thickness	v: Chin width	v: Chin longth	
06	Chipped	z: Chip thickness Z≦1/2t	y: Chip width Not over viewing area	x: Chip length x≤1/8a	2.5
	glass	1/2t <z≦2t< td=""><td>Not exceed 1/3k</td><td>x≦1/8a</td><td>2.0</td></z≦2t<>	Not exceed 1/3k	x≦1/8a	2.0
		⊙ If there are 2 or mo 6.1.2 Corner crack:	ore chips, x is total len	igth of each chip.	
		z: Chip thickness	y: Chip width	x: Chip length	
		Z≦1/2t	Not over viewing area	x≦1/8a	
		1/2t <z≦2t< td=""><td>Not exceed 1/3k</td><td>x≦1/8a</td><td></td></z≦2t<>	Not exceed 1/3k	x≦1/8a	
		⊙If there are 2 or mo	ore chips, x is the total	l length of each chip.	

NO	Item	Criterion	AQL
		Symbols: x: Chip length y: Chip width z: Chip thickness k: Seal width t: Glass thickness a: OLED side length L: Electrode pad length 6.2 Protrusion over terminal: 6.2.1 Chip on electrode pad:	
		6.2.2 Non-conductive portion:	
06	Glass crack	y Z Z X	2.5
		y: Chip width x: Chip length z: Chip	
		$ \begin{array}{c cccc} & & \text{thickness} \\ \hline y \leq L & x \leq 1/8a & 0 < z \leq t \end{array} $	
		⊙ If the chipped area touches the ITO terminal, over 2/3 of the ITO	
		must remain and be inspected according to electrode terminal	
		specifications. ⊙ If the product will be heat sealed by the customer, the alignment	
		mark not be damaged.	
		6.2.3 Substrate protuberance and internal crack.	
		y: width x: length	
		$y \le 1/3L$ $x \le a$	
		у	

NO	Item	Criterion	AQL
07	Cracked glass	The OLED with extensive crack is not acceptable.	2.5
08	Backlight elements	 8.1 Illumination source flickers when lit. 8.2 Spots or scratched that appear when lit must be judged. Using OLED spot, lines and contamination standards. 8.3 Backlight doesn't light or color wrong. 	0.65 2.5 0.65
09	Bezel	9.1 Bezel may not have rust, be deformed or have fingerprints, stains or other contamination.9.2 Bezel must comply with job specifications.	2.5 0.65
10	PCB、COB	 10.1 COB seal may not have pinholes larger than 0.2mm or contamination. 10.2 COB seal surface may not have pinholes through to the IC. 10.3 The height of the COB should not exceed the height indicated in the assembly diagram. 10.4 There may not be more than 2mm of sealant outside the seal area on the PCB. And there should be no more than three places. 10.5 No oxidation or contamination PCB terminals. 10.6 Parts on PCB must be the same as on the production characteristic chart. There should be no wrong parts, missing parts or excess parts. 10.7 The jumper on the PCB should conform to the product characteristic chart. 10.8 If solder gets on bezel tab pads, OLED pad, zebra pad or screw hold pad, make sure it is smoothed down. 	2.5 2.5 0.65 2.5 2.5 0.65 2.5
11	Soldering	 11.1 No un-melted solder paste may be present on the PCB. 11.2 No cold solder joints, missing solder connections, oxidation or icicle. 11.3 No residue or solder balls on PCB. 11.4 No short circuits in components on PCB. 	2.5 2.5 2.5 0.65

NO	Item	Criterion	AQL
12	General appearance	 12.1 No oxidation, contamination, curves or, bends on interface Pin (OLB) of TCP. 12.2 No cracks on interface pin (OLB) of TCP. 12.3 No contamination, solder residue or solder balls on product. 12.4 The IC on the TCP may not be damaged, circuits. 12.5 The uppermost edge of the protective strip on the interface pin must be present or look as if it cause the interface pin to sever. 12.6 The residual rosin or tin oil of soldering (component or chip component) is not burned into brown or black color. 12.7 Sealant on top of the ITO circuit has not hardened. 12.8 Pin type must match type in specification sheet. 12.9 OLED pin loose or missing pins. 12.10 Product packaging must the same as specified on packaging specification sheet. 12.11 Product dimension and structure must conform to product specification sheet. 	2.5 0.65 2.5 2.5 2.5 2.5 0.65 0.65 0.65 0.65

Check Item	Classification	Criteria
No Display	Major	
Missing Line	Major	
Pixel Short	Major	
Darker Short	Major	
Wrong Display	Major	
Un-uniform B/A x 100% < 70% A/C x 100% < 70%	Major	A Normal B Dark Fixel C Light Fixel

10. Precautions in use of OLED Modules

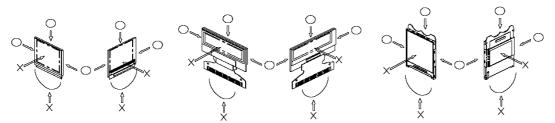
- (1) Avoid applying excessive shocks to module or making any alterations or modifications to it.
- (2) Don't make extra holes on the printed circuit board, modify its shape or change the components of OLED display module.
- (3) Don't disassemble the OLED display module.
- (4) Don't operate it above the absolute maximum rating.
- (5) Don't drop, bend or twist OLED display module.
- (6) Soldering: only to the I/O terminals.
- (7) Storage: please storage in anti-static electricity container and clean environment.
- (8) It's pretty common to use "Screen Saver" to extend the lifetime and Don't use fix information for long time in real application.
- (9) Don't use fixed information in OLED panel for long time, that will extend "screen burn" effect time.
- (10) DISPLAY has the right to change the passive components, including R2and R3 adjust resistors. (Resistors, capacitors and other passive components will have different appearance and color caused by the different supplier.)
- (11) DISPLAY have the right to change the PCB Rev. (In order to satisfy the supplying stability, management optimization and the best product performance...etc, under the premise of not affecting the electrical characteristics and external dimensions, DISPLAY have the right to modify the version.)

10.1 Handling Precautions

- (1) Since the display panel is being made of glass, do not apply mechanical impacts such us dropping from a high position.
- (2) If the display panel is broken by some accident and the internal organic substance leaks out, be careful not to inhale nor lick the organic substance.
- (3) If pressure is applied to the display surface or its neighborhood of the OLED display module, the cell structure may be damaged and be careful not to apply pressure to these sections.
- (4) The polarizer covering the surface of the OLED display module is soft and easily scratched. Please be careful when handling the OLED display module.
- (5) When the surface of the polarizer of the OLED display module has soil, clean the surface. It takes advantage of by using following adhesion tape.
- * Scotch Mending Tape No. 810 or an equivalent

Never try to breathe upon the soiled surface nor wipe the surface using cloth containing solvent Also, pay attention that the following liquid and solvent may spoil the polarizer:

- * Water
- * Ketone
- * Aromatic Solvents
- (6) Hold OLED display module very carefully when placing OLED display module into the System housing. Do not apply excessive stress or pressure to OLED display module. And, do not over bend the film with electrode pattern layouts. These stresses will influence the display performance. Also, secure sufficient rigidity for the outer cases.



- (7) Do not apply stress to the LSI chips and the surrounding molded sections.
- (8) Do not disassemble nor modify the OLED display module.
- (9) Do not apply input signals while the logic power is off.
- (10) Pay sufficient attention to the working environments when handing OLED display modules to prevent occurrence of element breakage accidents by static electricity.
- * Be sure to make human body grounding when handling OLED display modules.
- * Be sure to ground tools to use or assembly such as soldering irons.
- * To suppress generation of static electricity, avoid carrying out assembly work under dry environments.
- * Protective film is being applied to the surface of the display panel of the OLED display module. Be careful since static electricity may be generated when exfoliating the protective film.
- (11) Protection film is being applied to the surface of the display panel and removes the protection film before assembling it. At this time, if the OLED display module has been stored surface of the display panel after removed of the film. In such case, remove the residue material by the method introduced in the above Section 5.
- (12) If electric current is applied when the OLED display module is being dewed or when it is placed under high humidity environments, the electrodes may be corroded and be careful to avoid the above.

10.2 Storage Precautions

- (1) When storing OLED display modules, put them in static electricity preventive bags avoiding exposure to direct sun light nor to lights of fluorescent lamps. And, also, avoiding high temperature and high humidity environment or low temperature (less than 0°C) environments. (We recommend you to store these modules in the packaged state when they were shipped from DISPLAY. At that time, be careful not to let water drops adhere to the packages or bags nor let dewing occur with them.
- (2) If electric current is applied when water drops are adhering to the surface of the OLED display module, when the OLED display module is being dewed or when it is placed under high humidity environments, the electrodes may be corroded and be careful about the above.

10.3 Designing Precautions

- (1) The absolute maximum ratings are the ratings which cannot be exceeded for OLED display module, and if these values are exceeded, panel damage may be happen.
- (2) To prevent occurrence of malfunctioning by noise, pay attention to satisfy the VIL and VIH specifications and, at the same time, to make the signal line cable as short as possible.
- (3) We recommend you to install excess current preventive unit (fuses, etc.) to the power circuit (VDD). (Recommend value: 0.5A)
- (4) Pay sufficient attention to avoid occurrence of mutual noise interference with the neighboring devices.
- (5) As for EMI, take necessary measures on the equipment side basically.
- (6) When fastening the OLED display module, fasten the external plastic housing section.
- (7) If power supply to the OLED display module is forcibly shut down by such errors as taking out the main battery while the OLED display panel is in operation, we cannot guarantee the quality of this OLED display module. Connection (contact) to any other potential than the above may lead to rupture of the IC.